Notice of References Cited

Application/Control No 10/769,010		Applicant(s)/Patent Under Reexamination YOON ET AL.		
Examiner	Art Unit			
AHMED ELALLAM	2616	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US- 2006/0128410	06-2006	Derryberry et al	455/509
*	В	US-2003/0126238	07-2003	Kohno et al.	709/220
*	C	US-2003/0099211	05-2003	Moulsley et al.	370/328
*	D	US- 2002/0176362	11-2002	Yun et al	370/236
*	Е	US-2002/0154610	10-2002	Tiedemann et al.	370/329
*	F	US-2004/0160914	08-2004	Sarkar, Sandip	370/329
*	G	US-2004/0141525	07-2004	Bhushan et al.	370/473
*	Н	US- 7,206,280	04-2007	Khan et al	370/216
*	1	US-7,185,256	02-2007	Miki et al.	714/751
*	J	US- 7,155,236	12-2006	Chen et al	455/454
*	к	US- 6,954,448	10-2005	Farley et al	370/337
*	L	US-6,717,924	04-2004	Ho et al.	370/311
*	М	US- 6,694,469	02-2004	Jalali et al	714/748

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					,
	R					
	s					
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